

Preparation and Characterization of Organic Thin Films

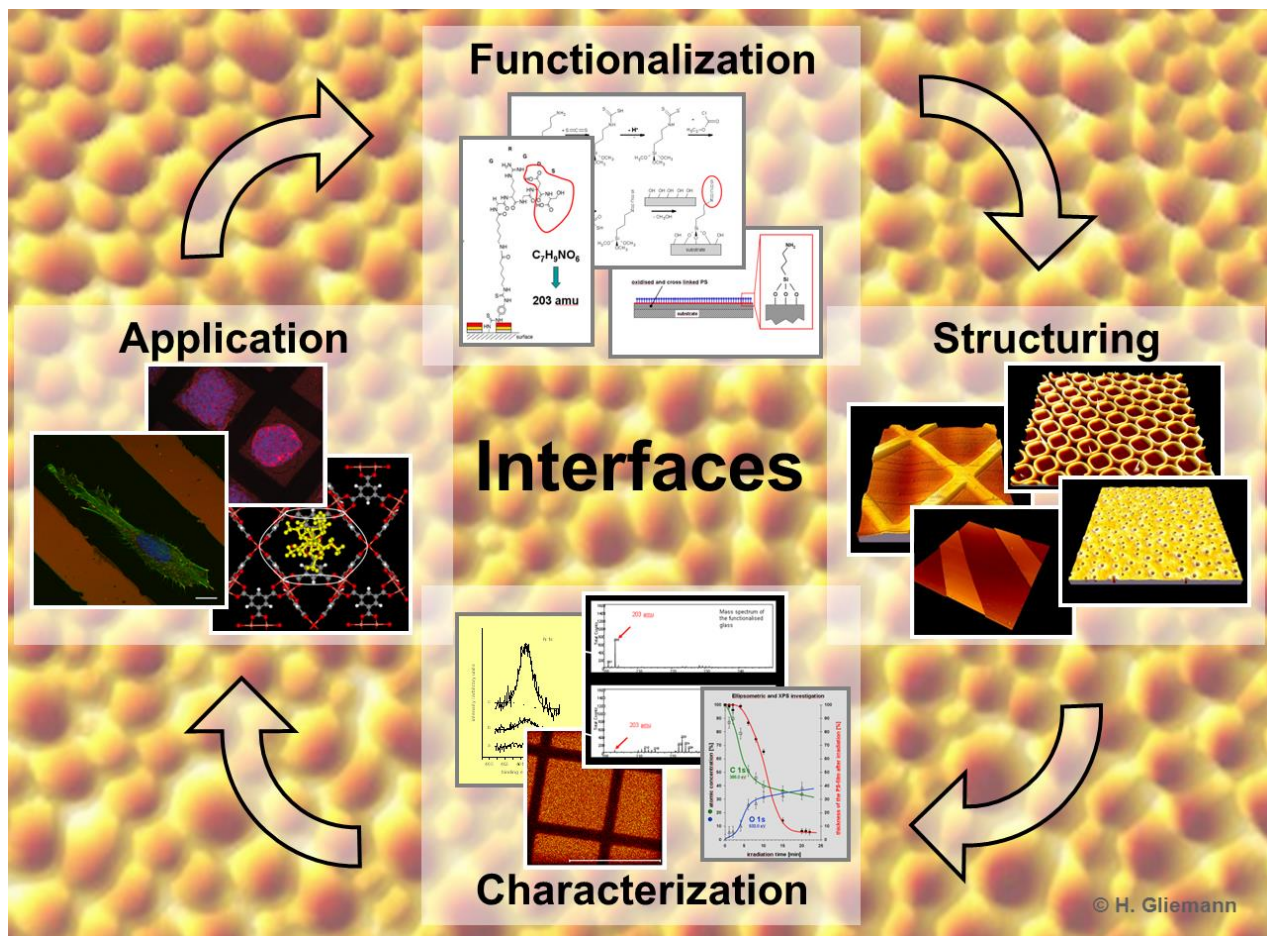
When: Mo., 3.4.2017 – Fr., 7.4.2017, 9:15 – 17:00

Where: 9:15 a.m. – 12.15 p.m. **CS / Building 30.44/ Room 408 (theoretical part)**
2:00 p.m. – 5:00 p.m. **CN / Building 330 (practical part)**

The course is designed for advanced students with a Bachelor in chemistry. Different methods for the preparation and structuring of organic thin films on metal and oxidic surfaces as well as different techniques for the (site-selective) surface characterization will be discussed. The theoretical introduction in the morning will be followed by a practical part in the afternoon. The course will be given in English language.

Registration via e-mail is necessary! Please contact : hartmut.gliemann@kit.edu

Registration deadline: Friday, 17.3.2017



Monday, 03.04.2017		
Morning (CS)	Introduction Self Assembled Monolayers (SAMs) Structuring of substrates and SAMs	
Afternoon (CN)	P: (preparation of stamps), SAMs on Au samples, μ CP	

Tuesday, 04.04.2017		
Morning (CS)	ToF-SIMS XPS	
Afternoon (CN)	P: XPS P: ToF-SIMS	

Wednesday, 05.04.2017		
Morning (CS)	Vibrational spectroscopy methods STM, AFM, SEM	
Afternoon (CN)	P: IR on patterned SAMs P: AFM	

Thursday, 06.04.2017		
Morning (CS)	SURMOFs XRD	
Afternoon (CN)	P: SURMOF preparation P: XRD on SURMOFs / evaluation	

Friday, 07.04.2017		
Morning (CS)	Optics at Surfaces/Interfaces (Ellipsometry) QCM	
Afternoon (CN)	P: Ellipsometry P: QCM	

Time table:

Building 30.44, room 408 (CS)

1 st morning session 9:15 - 10:45

Break: 10:45 – 11:00

2nd morning session 11:00 – 12:15

KIT shuttle CS → CN 12:30 – 12:50

Lunch break: 12:50 – 14:00

Seminar room IFG (CN)/Building 330/Room 356

Practical Part: 14:00 – 17:00